

• General Description

The CH100N03N combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

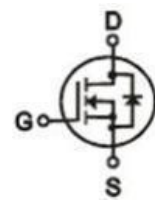
• Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

• Application

- SMPS 2nd Synchronous Rectifier
- BLDC Motor driver

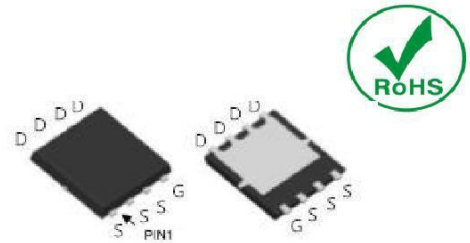
• Product Summary



$$V_{DS} = 30V$$

$$R_{DS(ON)} = 3.2m\Omega$$

$$I_D = 100A$$



DFN5 x 6

• Ordering Information:

| | |
|---------------------------|-----------|
| Part NO. | CH100N03N |
| Marking | CH100N03N |
| Packing Information | REEL TAPE |
| Basic ordering unit (pcs) | 5000 |

• Absolute Maximum Ratings (T_c = 25°C)

| Parameter | Symbol | Rating | Unit |
|-----------------------------------|------------------------|------------|------|
| Drain-Source Voltage | V_{DS} | 30 | V |
| Gate-Source Voltage | V_{GS} | ±20 | V |
| Continuous Drain Current | $I_{D@TC=25^\circ C}$ | 100 | A |
| | $I_{D@TC=75^\circ C}$ | 68 | A |
| | $I_{D@TC=100^\circ C}$ | 58 | A |
| Pulsed Drain Current ^① | I_{DM} | 360 | A |
| Total Power Dissipation(TC=25°C) | $P_D@TC=25^\circ C$ | 90 | W |
| Total Power Dissipation(TA=25°C) | $P_D@TA=25^\circ C$ | 2.8 | W |
| Operating Junction Temperature | T_J | -55 to 150 | °C |
| Storage Temperature | T_{STG} | -55 to 150 | °C |
| Avalanche Current | $I_{AS} I_{AR}$ | 40 | A |

● Thermal resistance

| Parameter | Symbol | Min. | Typ. | Max. | Unit |
|--|------------|------|------|------|---------------|
| Thermal resistance, junction - case | R_{thJC} | - | - | 3.1 | $^{\circ}C/W$ |
| Thermal resistance, junction - ambient | R_{thJA} | - | - | 50 | $^{\circ}C/W$ |
| Soldering temperature, wavesoldering for 10s | T_{sold} | - | - | 260 | $^{\circ}C$ |

● Electronic Characteristics

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|-----------------------------------|--------------|-------------------------------|------|-----|-----------|------------|
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 30 | | | V |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS}=V_{DS}, I_D=250\mu A$ | 1.2 | 1.6 | 2.5 | V |
| Drain-Source Leakage Current | I_{DSS} | $V_{DS}=60V, V_{GS}=0V$ | | | 1.0 | μA |
| Gate- Source Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | | | ± 100 | nA |
| Static Drain-source On Resistance | $R_{DS(ON)}$ | $V_{GS}=10V, I_D=30A$ | | 3.2 | 4.5 | m Ω |
| | | $V_{GS}=4.5V, I_D=20A$ | | 4.8 | 6.5 | m Ω |
| Forward Transconductance | g_{FS} | $V_{DS}=25V, I_D=10A$ | | 25 | | S |
| Source-drain voltage | VSD | $I_S=24A$ | | | 1.20 | V |

● Electronic Characteristics

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|------------------------------|-----------|---|------|------|------|------|
| Input capacitance | C_{iss} | $V_{DS}=15V$ $V_{GS}=0V$ $f=1MHz$ | - | 2700 | - | pF |
| Output capacitance | C_{oss} | | - | 320 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 240 | - | |

Gate Charge characteristics($T_a=25^{\circ}C$)

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|----------------------|----------|--------------|------|-----|------|------|
| Total gate charge | Q_g | $V_{DS}=15V$ | - | 42 | - | nC |
| Gate - Source charge | Q_{gs} | $I_D=30A$ | - | 4 | - | |
| Gate - Drain charge | Q_{gd} | $V_{GS}=10V$ | - | 14 | - | |

Note: ① Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;

N- Channel Typical Characteristics

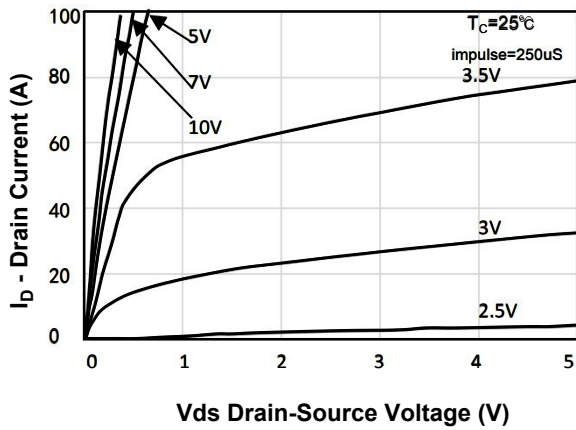


Figure 1. On-Region Characteristics

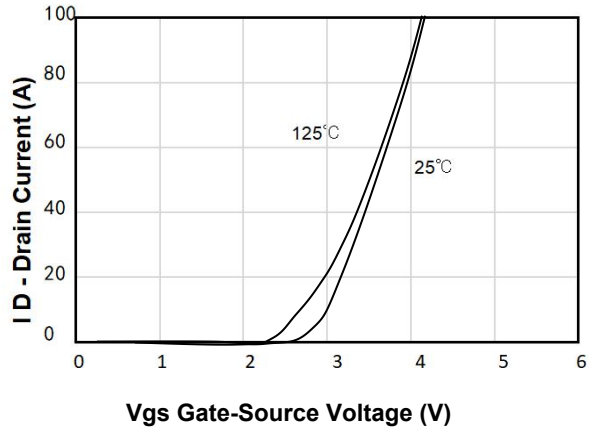


Figure 2. Transfer Characteristics

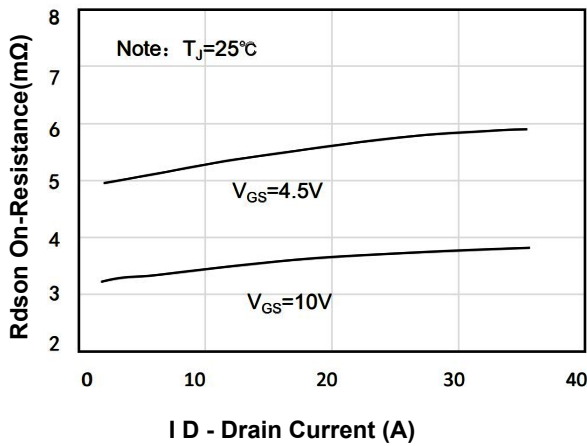


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

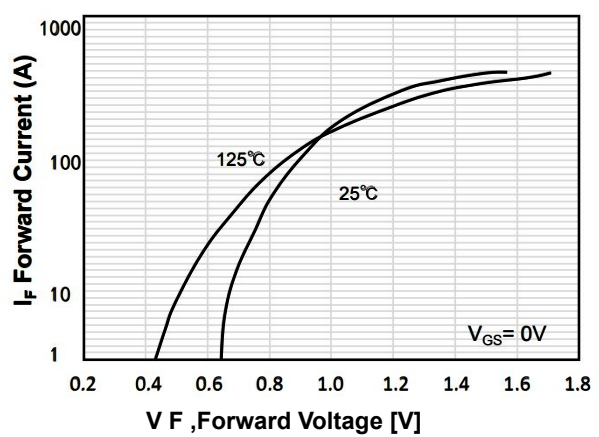


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

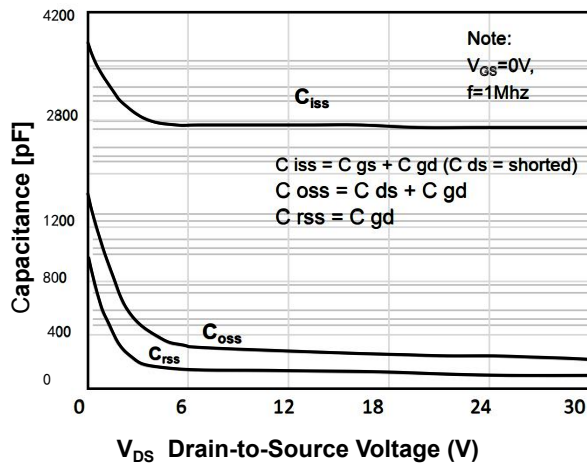


Figure 5. Capacitance Characteristics

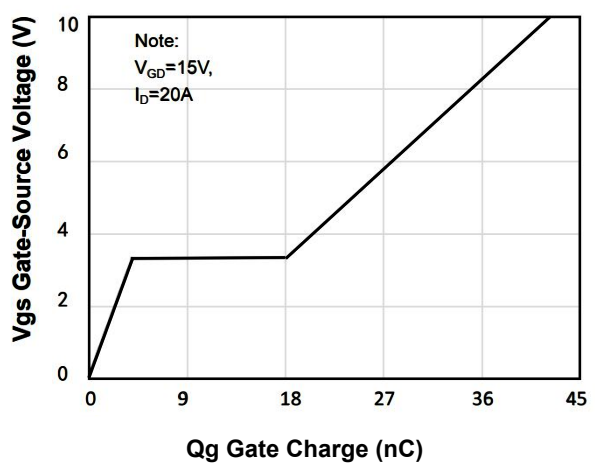


Figure 6. Gate Charge Characteristics

N- Channel Typical Characteristics (Continued)

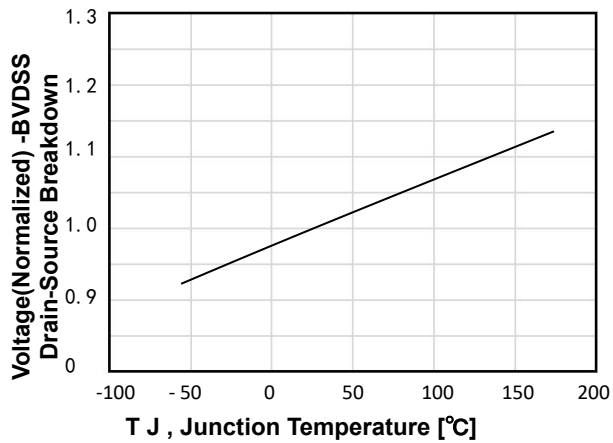


Figure 7. Breakdown Voltage Variation vs Temperature

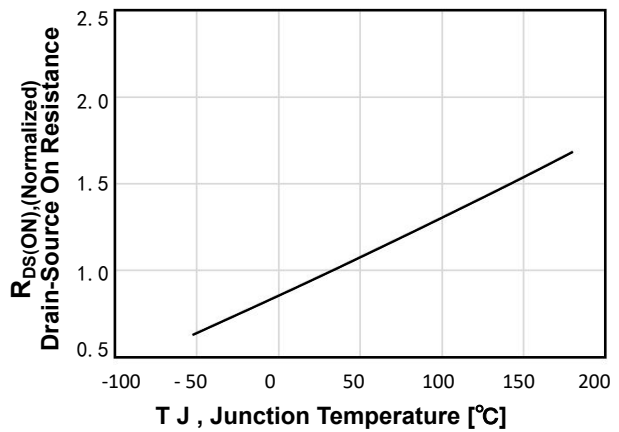


Figure 8. On-Resistance Variation vs Temperature

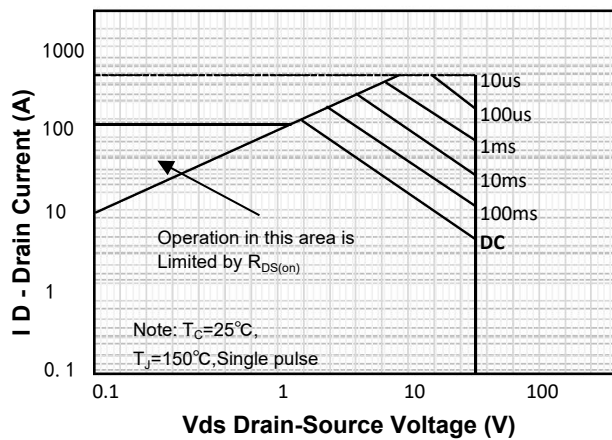


Figure 9. Maximum Safe Operating Area

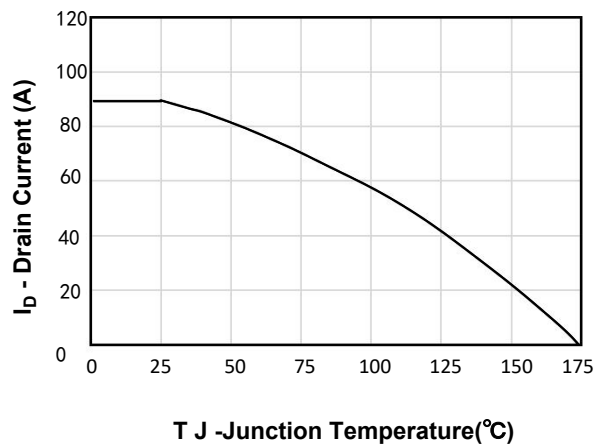


Figure 10. Maximum PContinuous Drain Current vs Case Temperature

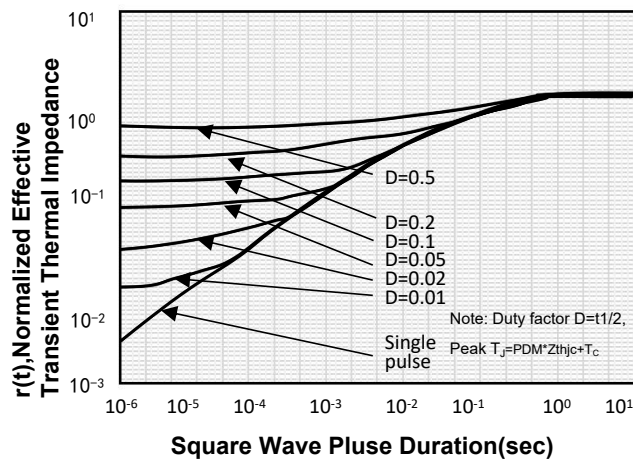
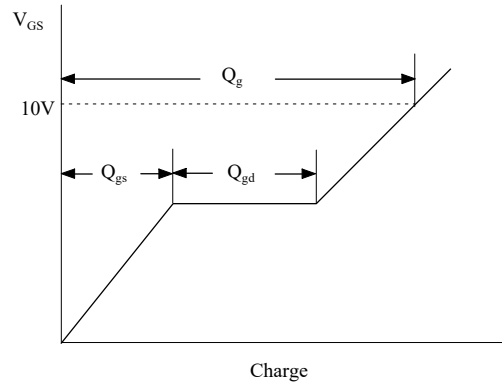
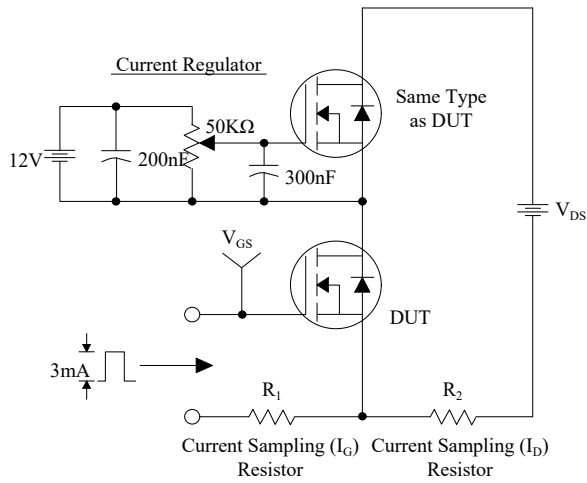
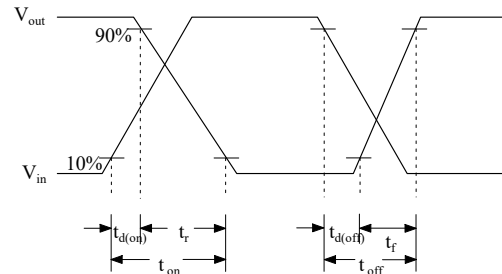
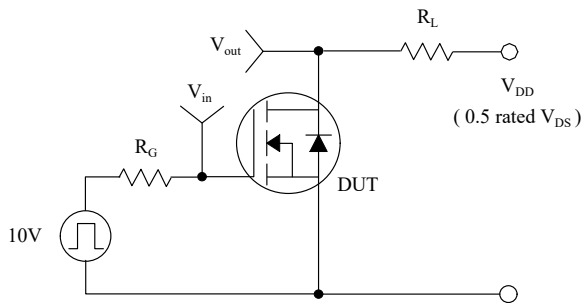


Figure 11. Transient Thermal Response Curve

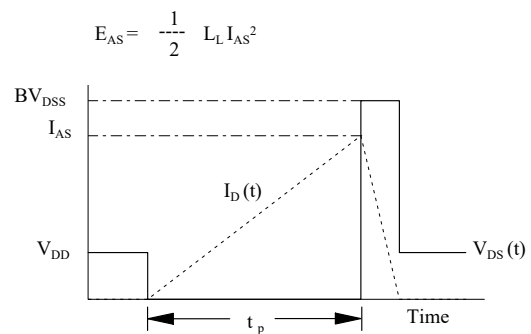
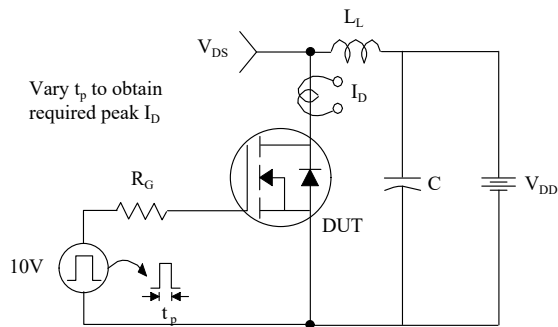
Gate Charge Test Circuit & Waveform



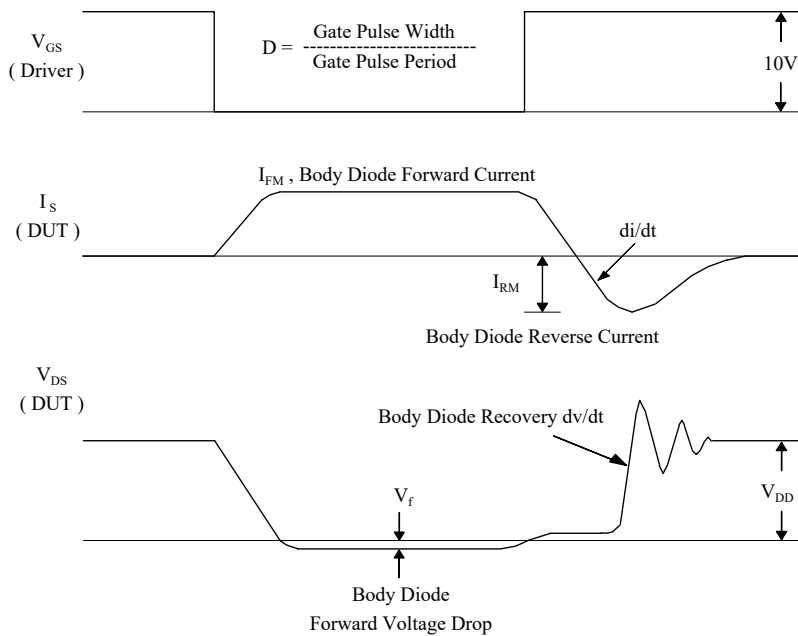
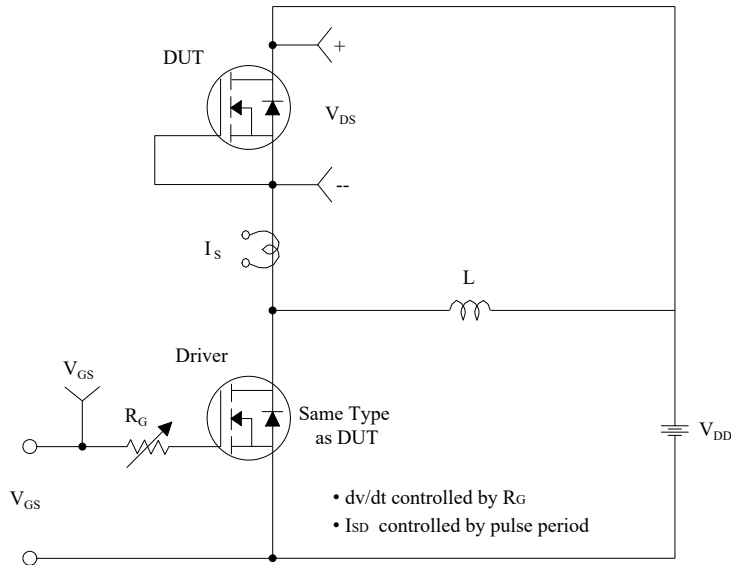
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

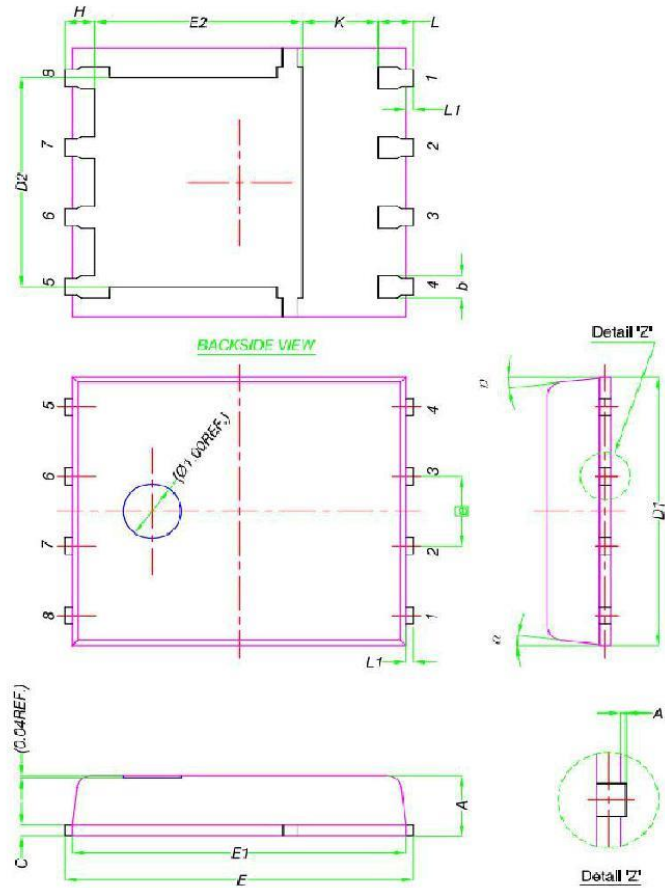


Peak Diode Recovery dv/dt Test Circuit & Waveforms



•Dimensions (DFN5×6)

Unit: mm



| DIM. | MILLIMETERS | | |
|----------|-------------|------|------|
| | MIN. | NOM. | MAX. |
| A | 0.90 | 1.00 | 1.10 |
| A1 | 0 | - | 0.05 |
| b | 0.33 | 0.41 | 0.51 |
| C | 0.20 | 0.25 | 0.30 |
| D1 | 4.80 | 4.90 | 5.00 |
| D2 | 3.61 | 3.81 | 3.96 |
| E | 5.90 | 6.00 | 6.10 |
| E1 | 5.70 | 5.75 | 5.80 |
| E2 | 3.38 | 3.58 | 3.78 |
| e | 1.27 BSC | | |
| H | 0.41 | 0.51 | 0.61 |
| K | 1.10 | - | - |
| L | 0.51 | 0.61 | 0.71 |
| L1 | 0.06 | 0.13 | 0.20 |
| α | 0° | - | 12° |